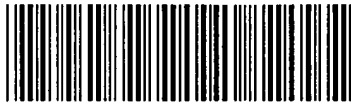


Search Notes

Application/Control No.

10/779,379

Examiner

Anh D. Mai

Applicant(s)/Patent under
Reexamination

CHAO, IWEN

Art Unit

2814

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST * See attached Search History	3/31/2006	A.M
IEEE Xplore: See attached Search	3/31/2006	A.M